

MVA tools to chose the jet combination

- **Introduction**
 - ♦ What has been checked and what was the aim?
- **Methods:**
 - ♦ Likelihood ratio and neural network approach with and without decorrelated variables as input
- **Plots and numbers**
 - ♦ Summary of results and conclusions
- **Next steps towards JEC estimation**

Petra Van Mulders

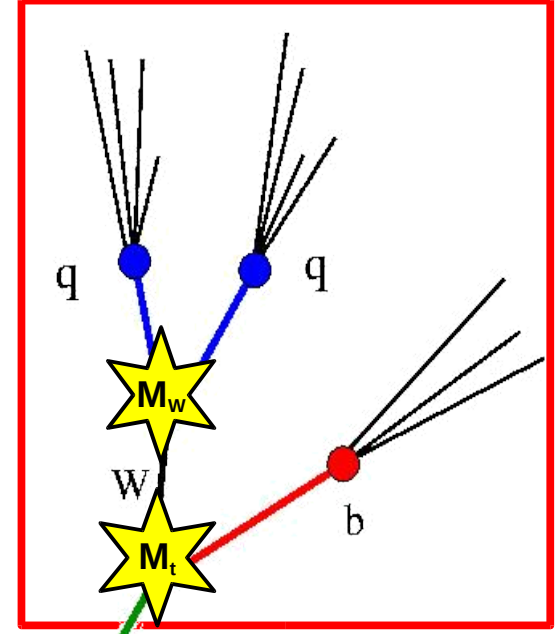
IIHE-Top Quark Meeting
May 6th 2009

- **Chose variables:**
 - High discriminating power
 - Stable ordering according to discriminating power after different event selections
 - Less then 40% correlated
 - No use of MET (not well known at startup)
 - < 20% correlation with hadronic W boson or top quark mass (to avoid bias)
- **Study 4 methods to combine the selected variables:**
 - Likelihood Ratio (LR) with and without decorrelated input variables
 - Neural Network (NN) with and without decorrelated input variables
- **Aim:**
 - Check purity versus efficiency when applying each of the 4 MVA methods (**performance**)
 - Check the effect of applying tight and less tight event selection:
 - On performance
 - On the jet combination with the highest MVA discriminant value: is the chosen jet combination the same in both cases? (**overlap**)

⇒ is it possible to study the event selection afterwards?

- **Semi-leptonic channel:**
 - Leptonic side used to select the event
 - Hadronic side is used to estimate the jet energy calibration factors
- **Need to identify the jets in the hadronic side:**
 - Application of the kinematic fit with the 2 mass constraints
 - Don't care about the b-jet at the leptonic side.
 - Use 4 highest p_T jets as input

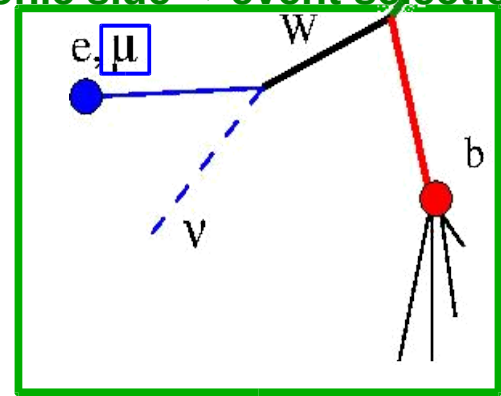
hadronic side → JEC estimate



LOOSE versus TIGHT selection cuts:

- $p_T(\text{jets}) > 30$ versus $40 \text{ GeV}/c$, $|\eta| < 2.4$
- $p_T(\mu) > 20$ versus $30 \text{ GeV}/c$, $|\eta| < 2.1$
- **μ isolated:**
 - $R_{\text{ellso}} > 0.90$ versus 0.95
 - $\text{VetoConeEM} < 6$ versus 4 GeV
 - $\text{VetoConeHAD} < 8$ versus 6 GeV

leptonic side → event selection/trigger

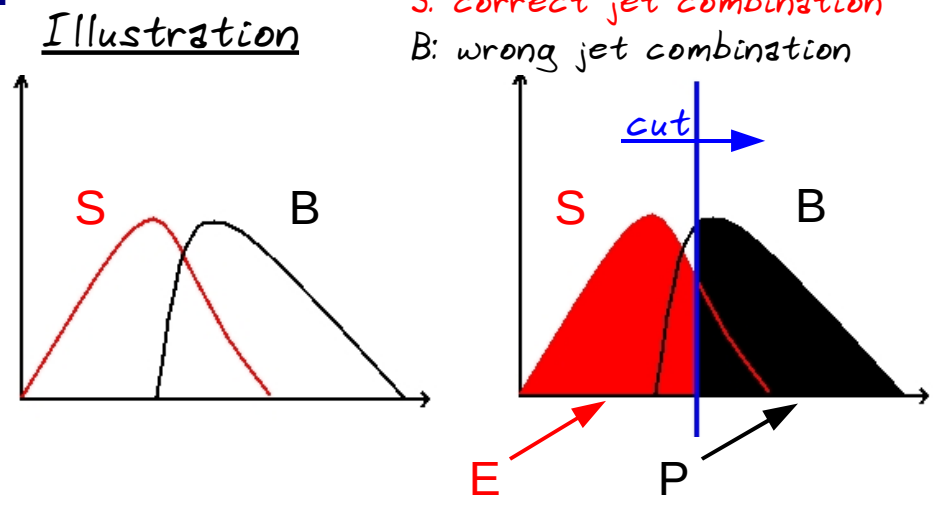


- **non-overlapping jets:**
 $\Delta R(\text{jet } i, \text{jet } j) > 1.0$

- **136 variables are implemented which can be put in different categories:**
 - cat. 1:** Mass, p_T , η , ϕ , θ of single candidates of the $t\bar{t}$ system
 - cat. 2:** Variables which compare 2 candidates of the $t\bar{t}$ system: Δm , ΔR , $\Delta\phi$ or $\Delta\Omega$.
 - cat. 3:** Special variables combining the p_T of the jets
 - cat. 4:** Variables based on b-tag information with 6 different b-tag algorithms
 - Hadronic b, Leptonic b, or combination of both (sum or multiplication)

▪ **Discriminating power of the variables?**

- **Surface method:** calculate the overlapping surface of the signal and background distributions: the smaller, the better!
- **PTE method:** the higher, the better!
 - search maximum of $P \cdot E$ while moving cut from left to right
 - search maximum of $P \cdot E$ while moving cut from right to left
 - take maximum of the 2 calculated maxima as handle on the discriminating power



- **Table of variables ordered according to discriminating power (2 definitions)**
 - **Do ordering again starting from the variable with the highest discriminating power and after the following requirements:**
 - **Remove variables related to MET**
 - **< 40% correlated with each other and < 20 % with m_W , m_t**

LOOSE		TIGHT	
SURFACE	PTE	SURFACE	PTE
bTagProdImpactParaMVA	bTagProdImpactParaMVA	bTagProdImpactParaMVA	bTagProdImpactParaMVA
bTagHadBTrkCntHighEff	bTagHadBTrkCntHighEff	bTagHadBTrkCntHighEff	bTagHadBTrkCntHighEff
bTagLepBTrkCntHighEff	bTagLepBTrkCntHighEff	bTagLepBTrkCntHighEff	relativePtHadronicTop
relativePtHadronicTop	relativePtHadronicTop	relativePtHadronicTop	bTagLepBTrkCntHighEff
$\Delta\Omega$ (HadTop,HadW)	$\Delta\Omega$ (LepB,Muon)	$\Delta\Omega$ (HadTop,HadW)	$\Delta\Omega$ (LepB,Muon)
$\Delta\Omega$ (LepB,Muon)	$\Delta\Omega$ (HadTop,LepB)	$\Delta\Omega$ (LepB,Muon)	$\Delta\Omega$ (HadW,LepB)
$\Delta\Omega$ (HadTop,LepB)	$\Delta\Omega$ (HadTop,Muon)	$\Delta\Omega$ (HadTop,HadB)	$\Delta\Omega$ (HadTop,Muon)
$\Delta\Omega$ (HadTop,HadB)	ΔR (HadB,LepB)	$\Delta\Omega$ (HadW,LepB)	$\Delta\Omega$ (HadTop,HadW)
$\Delta\Omega$ (HadTop,Muon)	θ HadW	$\Delta\Omega$ (HadTop,Muon)	$\Delta\Omega$ (HadB,LepB)
bTagSumSoftMuon	ΔR (HadB,Muon)	$\Delta\Omega$ (HadB,LepB)	$\Delta\phi$ (HadB,Muon)
ΔR (HadB,LepB)	$\Delta\Omega$ (HadTop,HadB)	$\Delta\phi$ (HadTop,Muon)	$\Delta\phi$ (HadTop,Muon)
ΔR (HadB,Muon)	$\Delta\phi$ (HadTop,Muon)	ΔR (HadB,Muon)	$\Delta\Omega$ (HadTop,HadB)

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Only 1 variable which makes use of b-tag information!

LOOSE		TIGHT	
SURFACE	PTE	SURFACE	PTE
bTagProdImpactParamVA	bTagProdImpactParamVA	bTagProdImpactParamVA	bTagProdImpactParamVA
bTagHadBTrkCntHighEff	bTagHadBTrkCntHighEff	bTagHadBTrkCntHighEff	bTagHadBTrkCntHighEff
bTagLepBTrkCntHighEff	bTagLepBTrkCntHighEff	bTagLepBTrkCntHighEff	bTagLepBTrkCntHighEff
relativePtHadronicTop	relativePtHadronicTop	relativePtHadronicTop	relativePtHadronicTop
$\Delta\Omega$ (HadTop,HadW)	$\Delta\Omega$ (LepB,Muon)	$\Delta\Omega$ (HadTop,HadW)	$\Delta\Omega$ (LepB,Muon)
$\Delta\Omega$ (LepB,Muon)	$\Delta\Omega$ (HadTop,LepB)	$\Delta\Omega$ (LepB,Muon)	$\Delta\Omega$ (HadW,LepB)
$\Delta\Omega$ (HadTop,LepB)	$\Delta\Omega$ (HadTop,Muon)	$\Delta\Omega$ (HadTop,HadB)	$\Delta\Omega$ (HadTop,Muon)
$\Delta\Omega$ (HadTop,HadB)	ΔR (HadB,LepB)	$\Delta\Omega$ (HadW,LepB)	$\Delta\Omega$ (HadTop,HadW)
$\Delta\Omega$ (HadTop,Muon)	θ HadW	$\Delta\Omega$ (HadTop,Muon)	$\Delta\Omega$ (HadB,LepB)
bTagSumSoftMuon	ΔR (HadB,Muon)	$\Delta\Omega$ (HadB,LepB)	$\Delta\phi$ (HadB,Muon)
ΔR (HadB,LepB)	$\Delta\Omega$ (HadTop,HadB)	$\Delta\phi$ (HadTop,Muon)	$\Delta\phi$ (HadTop,Muon)
ΔR (HadB,Muon)	$\Delta\phi$ (HadTop,Muon)	ΔR (HadB,Muon)	$\Delta\Omega$ (HadTop,HadB)

- **Table of variables ordered according to discriminating power (2 definitions)**
 - **Do ordering again starting from the variable with the highest discriminating power and after the following requirements:**
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 - **< 40% correlated with each other and < 20 % with m_W , m_t**

LOOSE		TIGHT	
SURFACE	PTE	SURFACE	PTE
bTagProdImpactParamVA	bTagProdImpactParamVA	bTagProdImpactParamVA	bTagProdImpactParamVA
bTagHadBTrkCntHighEff	bTagHadBTrkCntHighEff	bTagHadBTrkCntHighEff	bTagHadBTrkCntHighEff
bTagLepBTrkCntHighEff	bTagLepBTrkCntHighEff	bTagLepBTrkCntHighEff	bTagLepBTrkCntHighEff
relativePtHadronicTop	relativePtHadronicTop	relativePtHadronicTop	relativePtHadronicTop
$\Delta\Omega$ (HadTop,HadW)	$\Delta\Omega$ (LepB,Muon)	$\Delta\Omega$ (HadTop,HadW)	$\Delta\Omega$ (LepB,Muon)
$\Delta\Omega$ (LepB,Muon)	$\Delta\Omega$ (HadTop,LepB)	$\Delta\Omega$ (LepB,Muon)	$\Delta\Omega$ (HadW,LepB)
$\Delta\Omega$ (HadTop,LepB)	$\Delta\Omega$ (HadTop,Muon)	$\Delta\Omega$ (HadTop,HadB)	$\Delta\Omega$ (HadTop,Muon)
$\Delta\Omega$ (HadTop,HadB)	ΔR (HadB,LepB)	$\Delta\Omega$ (HadW,LepB)	$\Delta\Omega$ (HadTop,HadW)
$\Delta\Omega$ (HadTop,Muon)	θ_{HadW}	$\Delta\Omega$ (HadTop,Muon)	$\Delta\Omega$ (HadB,LepB)
bTagSumSoftMuon	ΔR (HadB,Muon)	$\Delta\Omega$ (HadB,LepB)	$\Delta\phi$ (HadB,Muon)
ΔR (HadB,LepB)	$\Delta\Omega$ (HadTop,HadB)	$\Delta\phi$ (HadTop,Muon)	$\Delta\phi$ (HadTop,Muon)
ΔR (HadB,Muon)	$\Delta\phi$ (HadTop,Muon)	ΔR (HadB,Muon)	$\Delta\Omega$ (HadTop,HadB)

PTE is sensitive to the fact that the signal and background distributions cross each other several times (in any case result the same, but preference for surface method)

- Table of variables ordered according to discriminating power (2 definitions)
 - Do ordering again starting from the variable with the highest discriminating power and after the following requirements:
 - Remove variables related to MET
 - < 40% correlated with each other and < 20 % with m_W , m_t

	LOOSE		TIGHT	
	SURFACE	PTE	SURFACE	PTE
use 7 first variables	bTagProdImpactParamMVA	bTagProdImpactParamMVA	bTagProdImpactParamMVA	bTagProdImpactParamMVA
	bTagHadBTrkCntHighEff	bTagHadBTrkCntHighEff	bTagHadBTrkCntHighEff	bTagHadBTrkCntHighEff
	bTagLepBTrkCntHighEff	bTagLepBTrkCntHighEff	bTagLepBTrkCntHighEff	bTagLepBTrkCntHighEff
	relativePtHadronicTop	relativePtHadronicTop	relativePtHadronicTop	relativePtHadronicTop
	$\Delta\Omega$ (HadTop,HadW)	$\Delta\Omega$ (LepB,Muon)	$\Delta\Omega$ (HadTop,HadW)	$\Delta\Omega$ (LepB,Muon)
	$\Delta\Omega$ (LepB,Muon)	$\Delta\Omega$ (HadTop,LepB)	$\Delta\Omega$ (LepB,Muon)	$\Delta\Omega$ (HadW,LepB)
	$\Delta\Omega$ (HadTop,LepB)	$\Delta\Omega$ (HadTop,Muon)	$\Delta\Omega$ (HadTop,HadB)	$\Delta\Omega$ (HadTop,Muon)
	$\Delta\Omega$ (HadTop,HadB)	ΔR (HadB,LepB)	$\Delta\Omega$ (HadW,LepB)	$\Delta\Omega$ (HadTop,HadW)
	$\Delta\Omega$ (HadTop,Muon)	θHadW	$\Delta\Omega$ (HadTop,Muon)	$\Delta\Omega$ (HadB,LepB)
	bTagSumSoftMuon	ΔR (HadB,Muon)	$\Delta\Omega$ (HadB,LepB)	$\Delta\phi$ (HadB,Muon)
ΔR (HadB,LepB)	$\Delta\Omega$ (HadTop,HadB)	$\Delta\phi$ (HadTop,Muon)	$\Delta\phi$ (HadTop,Muon)	
ΔR (HadB,Muon)	$\Delta\phi$ (HadTop,Muon)	ΔR (HadB,Muon)	$\Delta\Omega$ (HadTop,HadB)	

Correlation is 77%: so we can conclude that they contain the same information

Check for the 7 chosen variables if the correlation is the same after applying the loose or tight event selection

- Var1: $\Delta\Omega$ (HadTop,HadB)
- Var2: $\Delta\Omega$ (HadTop,LepB)
- Var3: $\Delta\Omega$ (HadTop,Muon)
- Var4: $\Delta\Omega$ (HadTop.HadW)
- Var5: $\Delta\Omega$ (LepB,Muon)
- Var6: relativePtHadTop
- Var7: bTagProdIPMVA

loose/tight

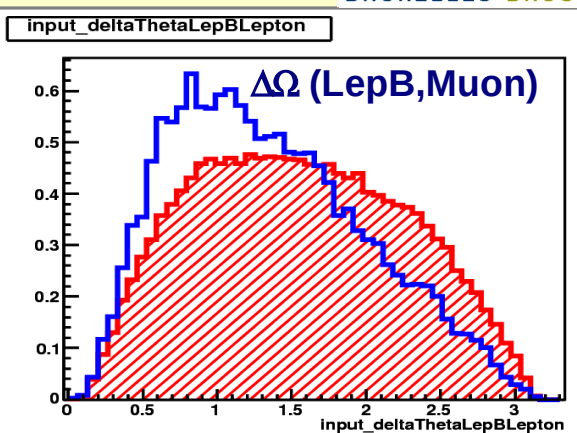
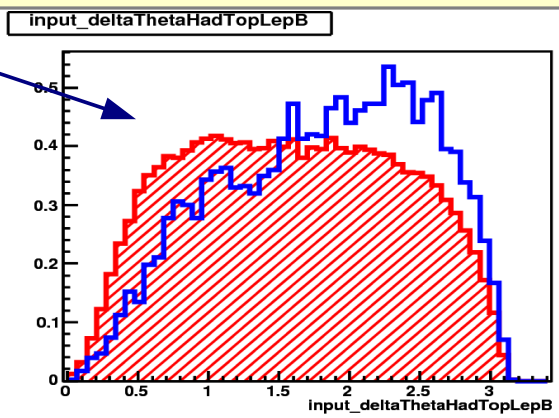
	Var1	Var2	Var3	Var4	Var5	Var6	Var7
Var1	100	8.9 / 9.6	16.0 / 17.5	13.8 / 14.7	3.2 / 0.6	13.0 / 15.3	0.4 / 0.5
Var2	8.9 / 9.6	100	9.6 / 9.5	-16.3 / -16.1	6.3 / 7.0	-11.1 / -11.4	1.2 / 3.9
Var3	16.0 / 17.5	9.6 / 9.5	100	14.3 / 13.8	11.8 / 10.9	23.8 / 24.1	2.5 / 1.1
Var4	13.8 / 14.7	-16.3 / -16.1	14.3 / 13.8	100	9.2 / 10.4	-16.5 / -16.9	0.9 / -3.9
Var5	3.2 / 0.6	6.3 / 7.0	11.8 / 10.9	9.2 / 10.4	100	-25.9 / -31.1	-4.2 / -6.5
Var6	13.0 / 15.3	-11.1 / -11.4	23.8 / 24.1	-16.5 / -16.9	-25.9 / -31.1	100	5.0 / 5.4
Var7	0.4 / 0.5	1.2 / 3.9	2.5 / 1.1	0.9 / -3.9	-4.2 / -6.5	5.0 / 5.4	100

The correlations are the same within less then 5%.

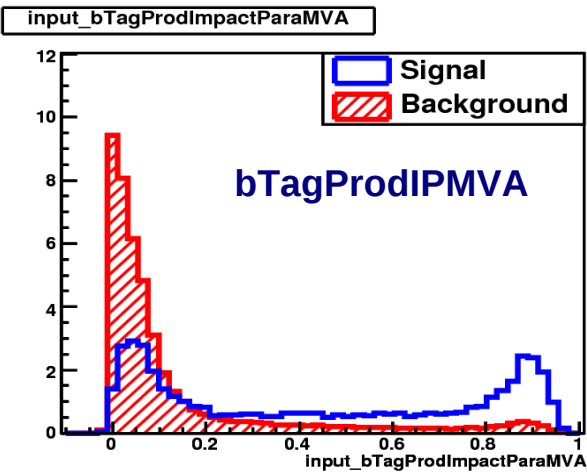
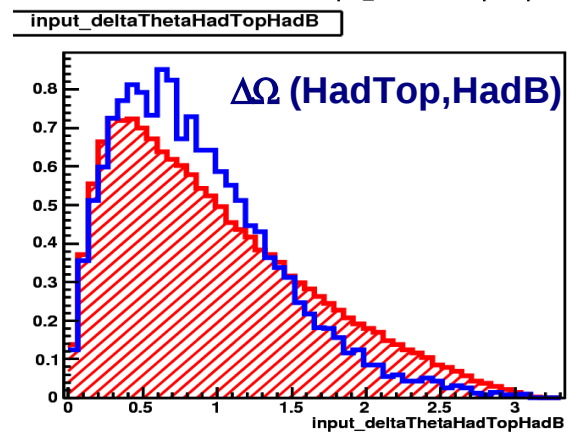
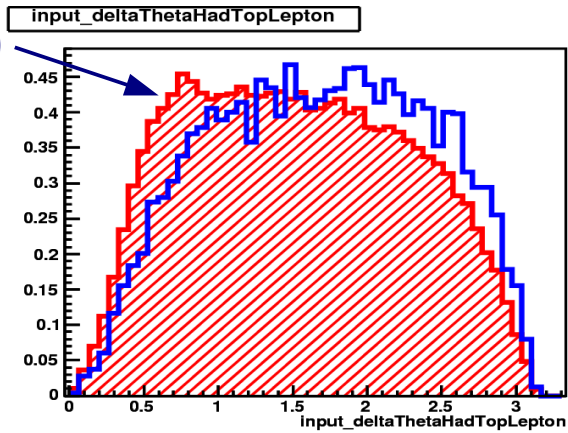
numbers in %

The 7 chosen variables

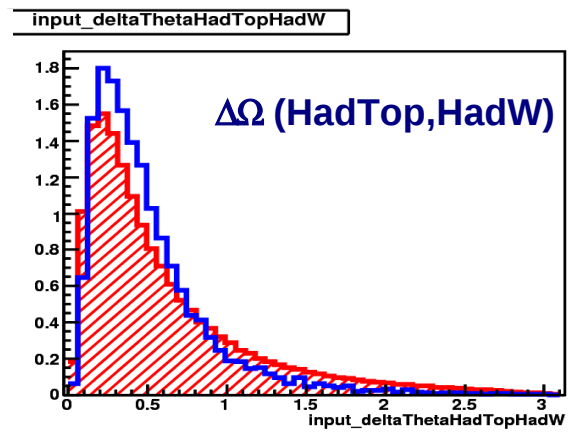
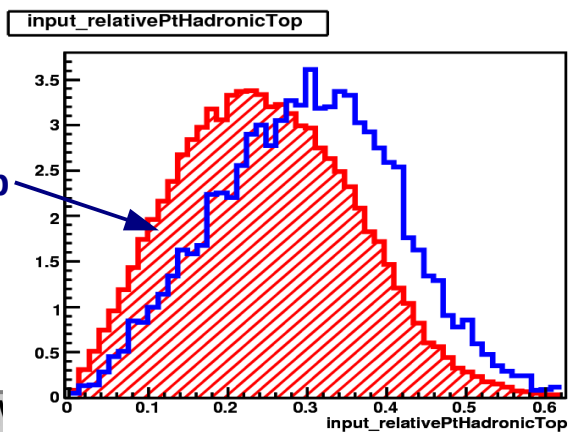
$\Delta\Omega$ (HadTop,LepB)



$\Delta\Omega$ (HadTop,Muon)



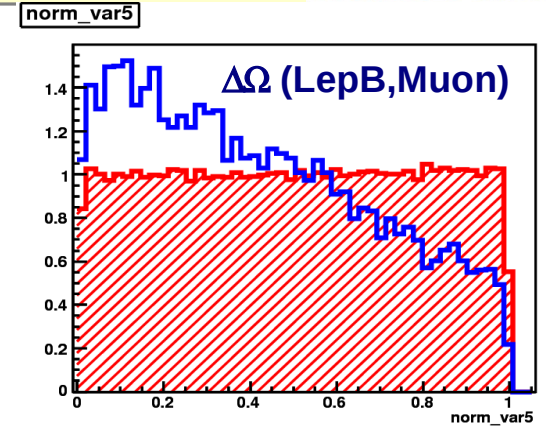
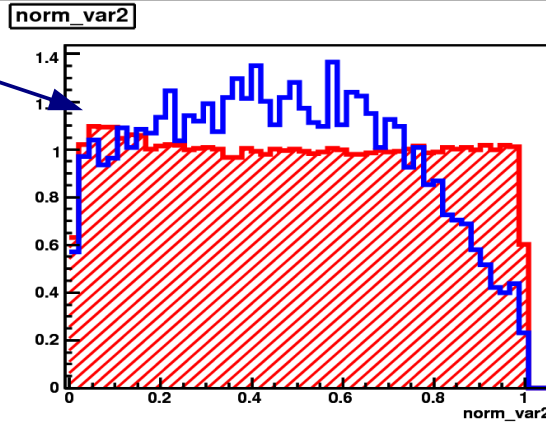
relativePtHadTop



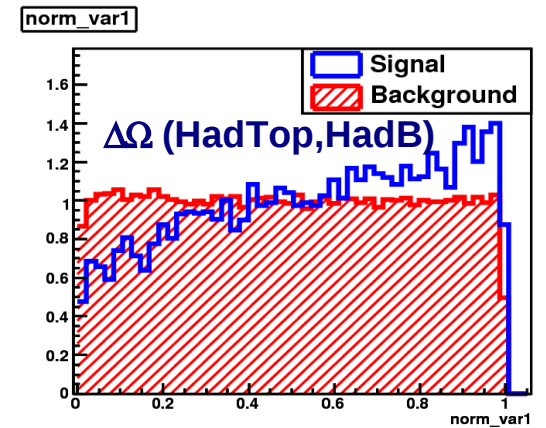
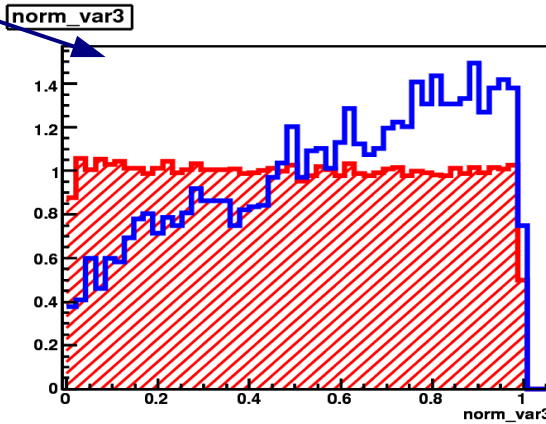
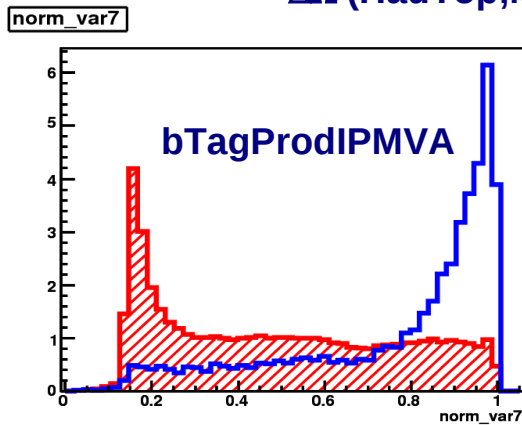
Normalized variables

$\Delta\Omega$ (HadTop,LepB)

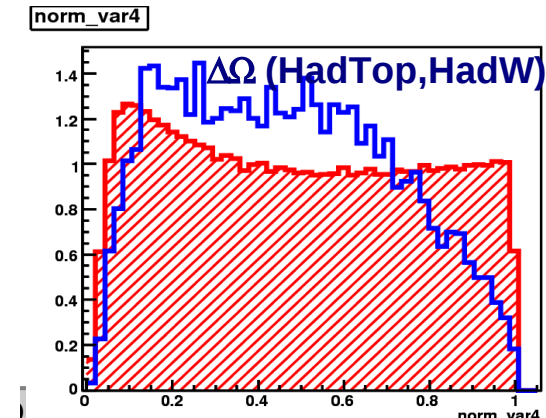
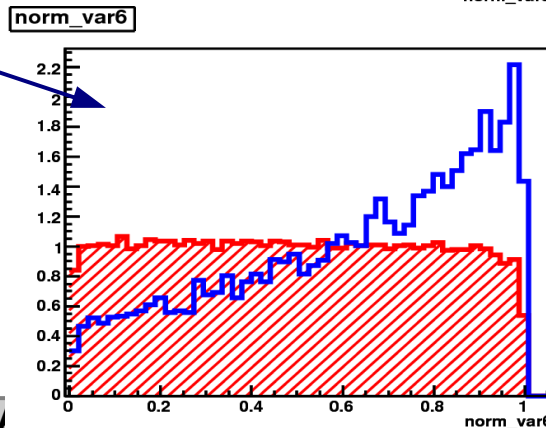
variables are normalized
to 1 on y-axis
x-axis: between 0 and 1



$\Delta\Omega$ (HadTop,Muon)

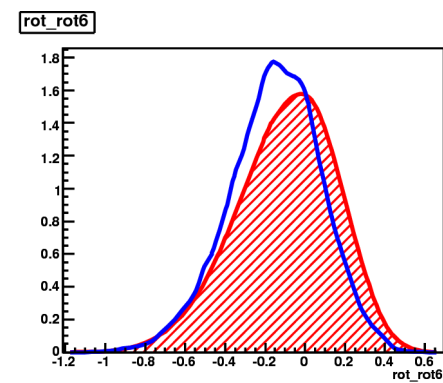
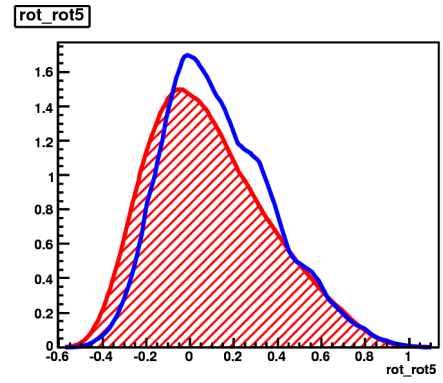
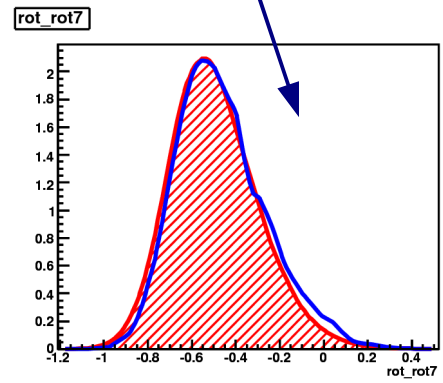
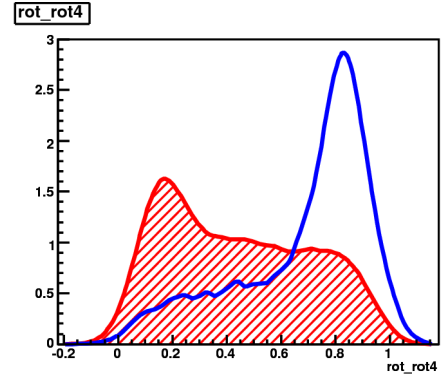
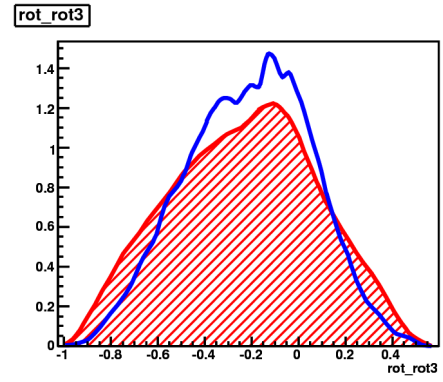
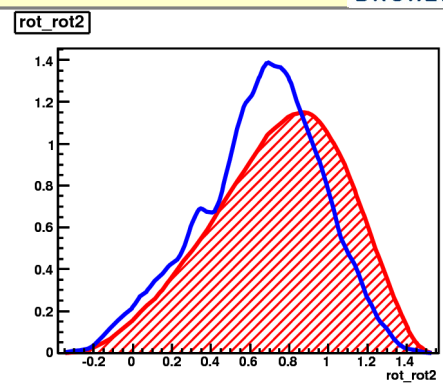
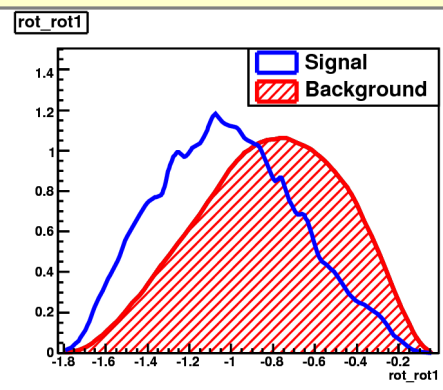


relativePtHadTop



**7 decorrelated variables:
no clear correspondance
between the 7 initial variables**

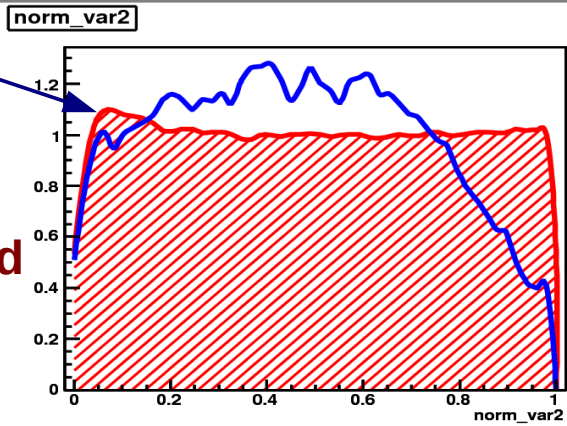
**no extra information:
can be dropped (not done)**



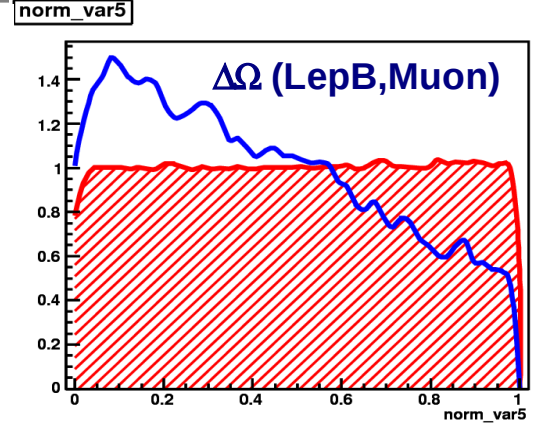
Variables as input for LR or NN

The (rotated) distributions are smoothened and combined by a LR or NN

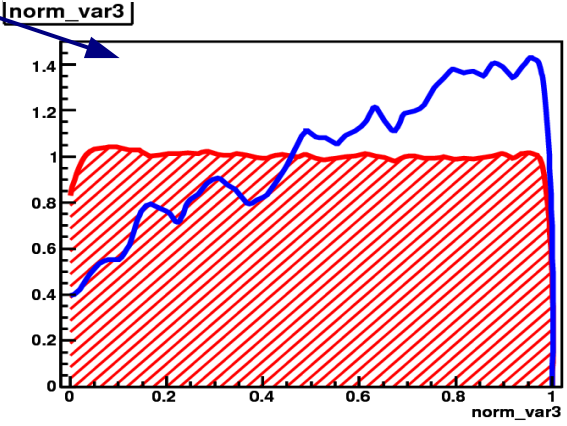
$\Delta\Omega$ (HadTop,LepB)



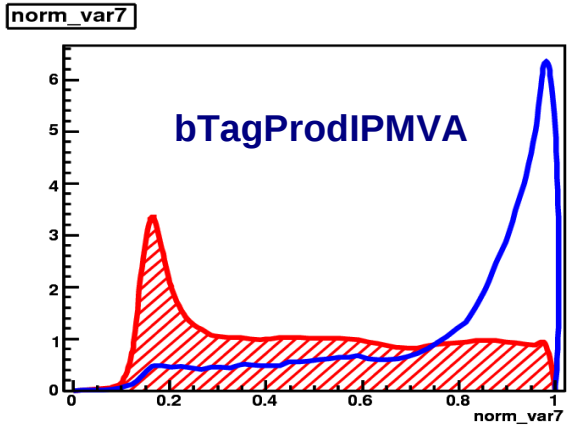
$\Delta\Omega$ (LepB,Muon)



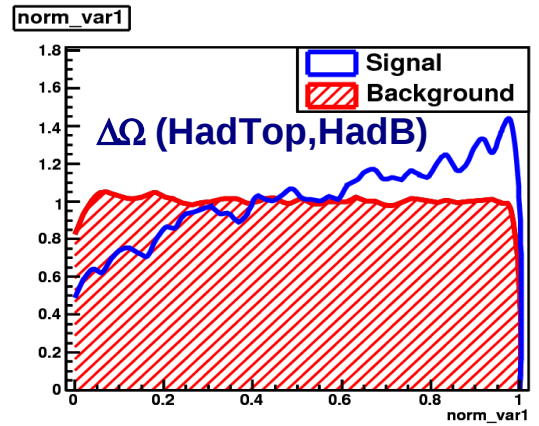
$\Delta\Omega$ (HadTop,Muon)



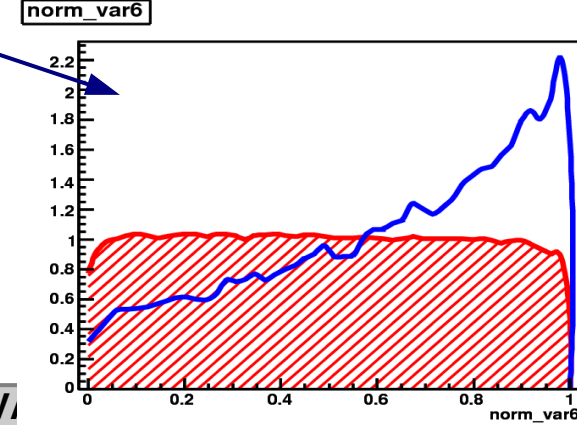
bTagProdIPMVA



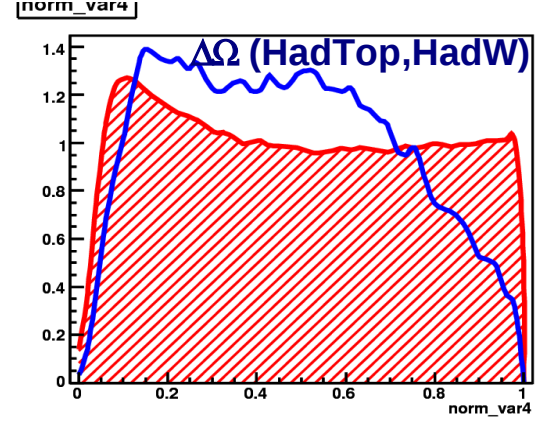
$\Delta\Omega$ (HadTop,HadB)



relativePtHadTop



$\Delta\Omega$ (HadTop,HadW)

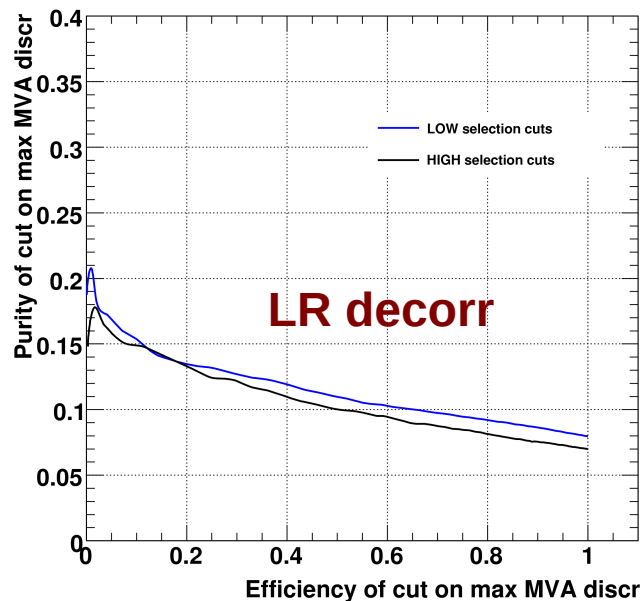
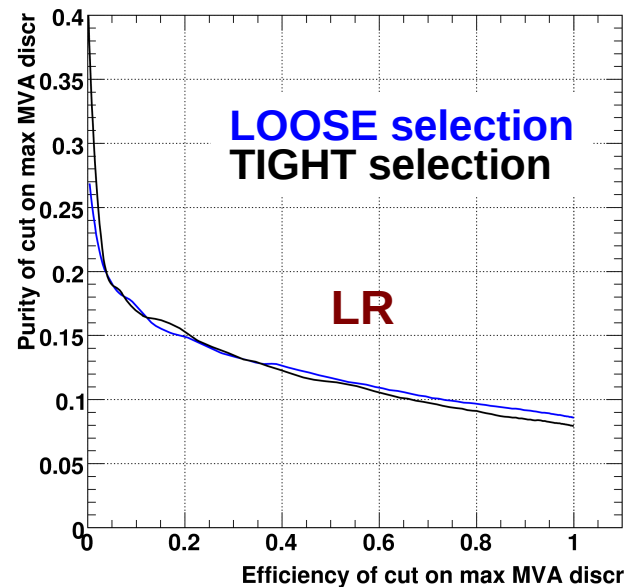


- Among the selected events using a loose event selection the subsample of events which were selected after a tight event selection is found.
- The discriminator for each jet combination and each event in the subsample has been calculated with 2 different mva-files according to the loose or tight event selection.
- We want to know in how many of the events the best jet combination (i.e. the jet combination with the highest discriminator) is the same after using a different input mva-file (i.e. using a different event selection)

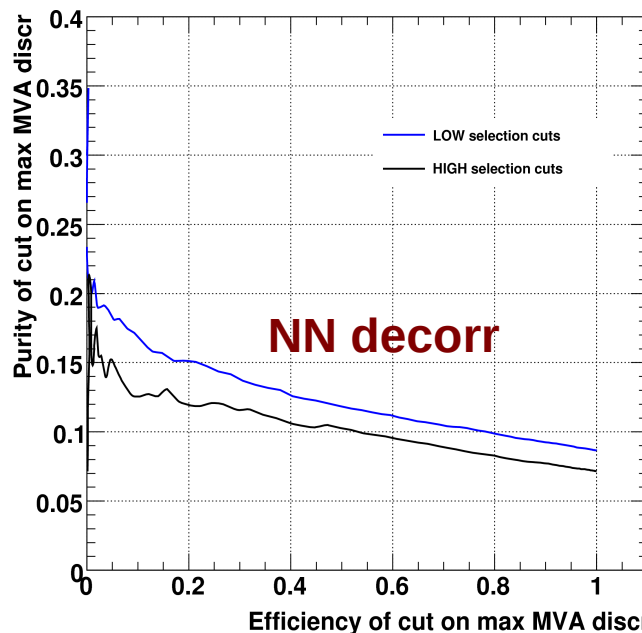
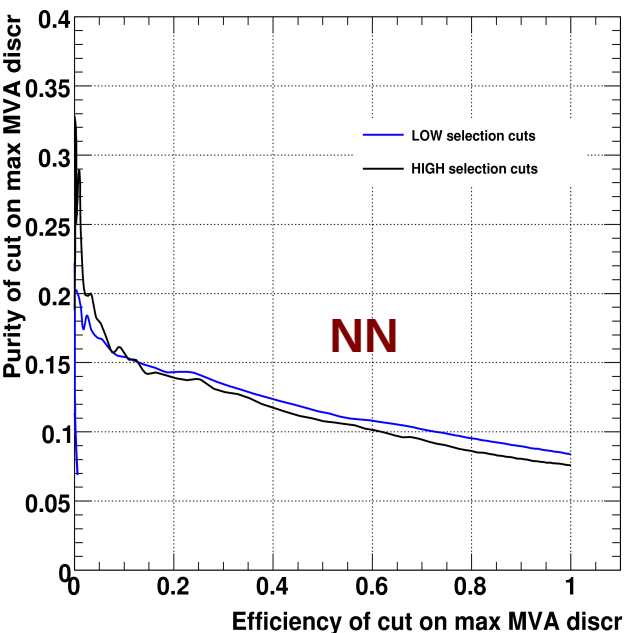
	LR	LR decorr	NN	NN decorr
no cut	87.2	78.2	84.3	81.5
0.2	87.3	78.3	84.3	81.6
0.4	87.6	79.3	85.2	81.0
0.6	86.9	79.8	83.8	79.4
0.7	85.7	78.6	83.8	80.4
0.8	85.7	75.9	81.4	78.8
0.9	84.5	55.8	70.8	71.3

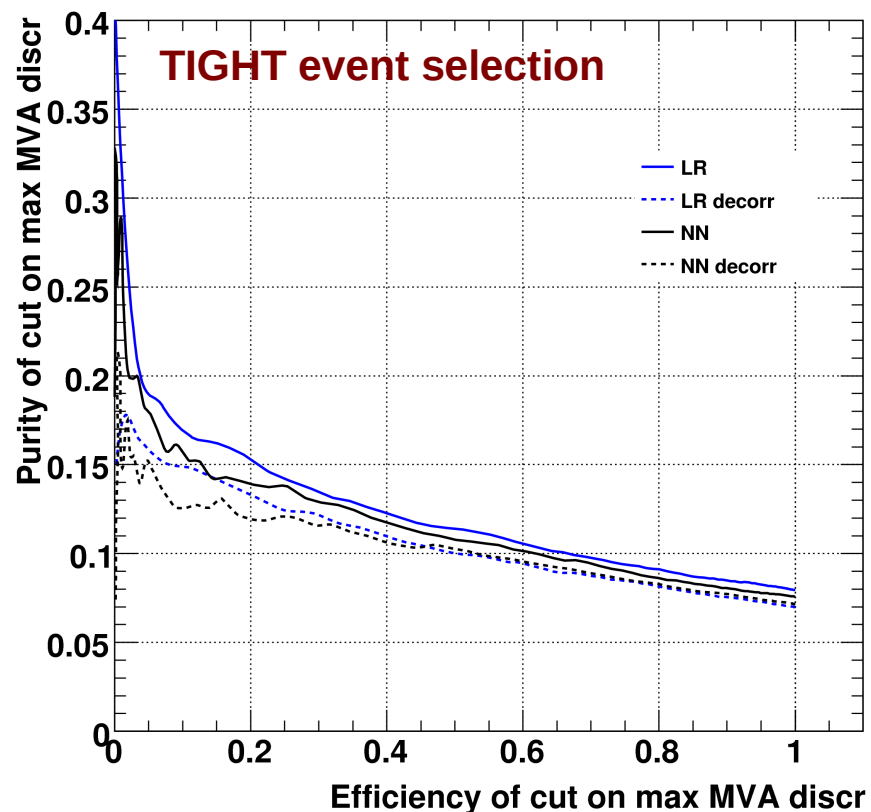
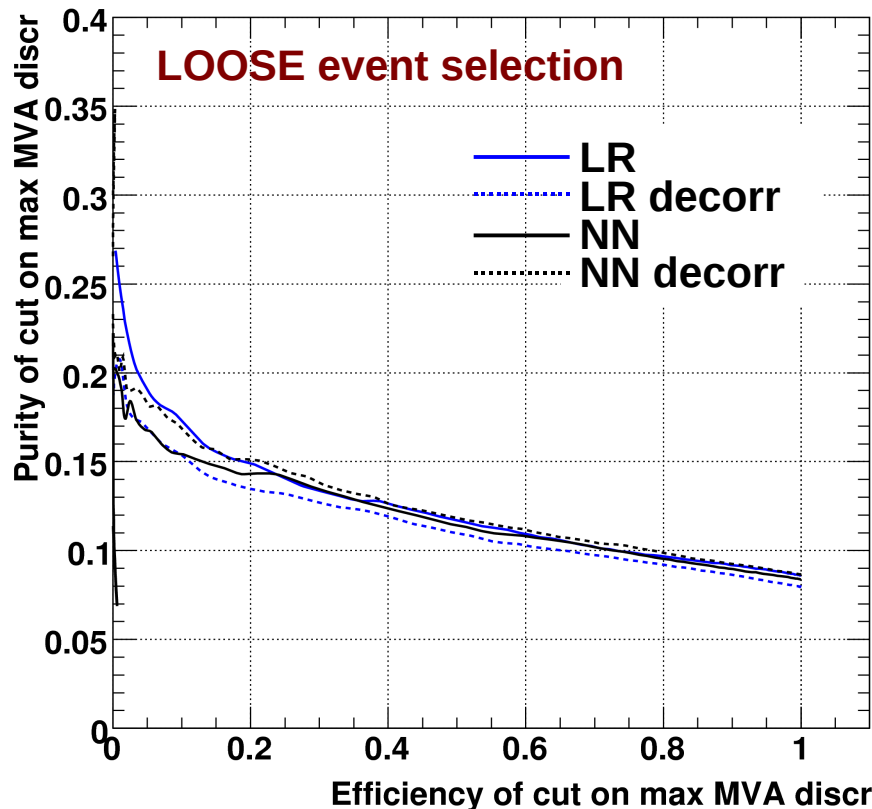
numbers in %

- The LR method has the highest percentage of events between the sample with high and low selection cuts in which the same jet combination is chosen.
- Check the performance of the different MVA tools:
purity of the cut on the MVA discriminant versus the efficiency of this cut



**Within 1-3% (NN decorr)
the performance of a
MVA method after the
loose or tight event
selection is the same**





- All the methods show a **similar performance within 1-2% at high efficiencies and 5% at low efficiencies**
- We see that the difference in performance is a bit bigger for the sample where the tight event selection has been applied: here the **LR is favored**
- Another reason to chose for the LR is that it has the **biggest overlap (slide 14)!**
- Previous slide: LR has the least difference in performance w.r.t event selection

- **7 variables with good discriminating power** were selected to be used as input for the MVA tools
- **All MVA methods yield a similar performance** in purity versus efficiency plots
- The methods give a similar performance after applying loose or tight event selection cuts
- **LR highest overlap of choosing same jet combination (87%)**, hence I chose this method for the continuation of my analysis

Given the previous bullets we can answer the question:

Is it possible to study the event selection later?

- **It's safe to apply the loose selection cuts** and refine the cuts after an event selection study has been done.
- Because of this conclusion I started the production of the ROOT-files needed for my analysis. This production is in the meantime almost done for signal and background samples.

Next steps:

- **Study event selection**
- **Perform estimation of the jet energy correction factors with and without differentiation as a function of p_T and η**
- ... many other things ...

